## Notice of References Cited Application/Control No. 10/588,644 Examiner Khai M. Nguyen Applicant(s)/Patent Under Reexamination HEEB, THIERRY Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,224,728	05-2007	Komamura, Mitsuya	375/238
*	В	US-6,606,044	08-2003	Roeckner et al.	341/143
*	C	US-6,473,457	10-2002	Pascual et al.	375/238
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	1	US-			*
	J	US-			
	K	US-			
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## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	· Classification
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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